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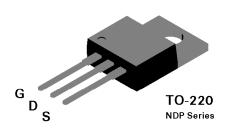
NDP6030PL / NDB6030PL P-Channel Logic Level Enhancement Mode Field Effect Transistor

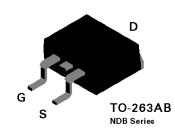
General Description

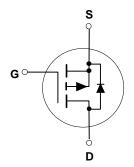
These P-Channel logic level enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage applications such as DC/DC converters and high efficiency switching circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- Critical DC electrical parameters specified at elevated temperature.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- High density cell design for extremely low R_{DS(ON)}.
- 175°C maximum junction temperature rating.







Absolute Maximum Ratings T_c

T.	=	25°C	unless	otherwise	noted
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Symbol	Parameter	NDP6030PL	NDB6030PL	Units	
V _{DSS}	Drain-Source Voltage		V		
V _{GSS}	Gate-Source Voltage - Continuous	Ė	V		
I _D	Drain Current - Continuous		-30		
	- Pulsed		90		
P _D	Total Power Dissipation @ T _C = 25°C		75	W	
	Derate above 25°C		0.5		
T _J ,T _{STG}	Operating and Storage Temperature Range	-65	-65 to 175		
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	2	275	°C	
T _J ,T _{STG}	Operating and Storage Temperature Range	-65	to 175	°C	
THERMA	L CHARACTERISTICS				
R _{θJC}	Thermal Resistance, Junction-to-Case	2		°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	6	2.5	°C/W	

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
OFF CHAR	ACTERISTICS	<u>.</u>		•		•	•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$		-30			V
Δ BV _{DSS} / Δ T _J	Breakdown Voltage Temp. Coefficient	I _D = -250 μA, Reference	I _D = -250 μA, Referenced to 25 °C		-36		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$				-250	μA
			T _J = 125°C			1	mA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 16 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -16 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHARA	CTERISTICS (Note)	•		3	•	3	•
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp.Coefficient	I _D = -250 μA, Reference	I _D =-250 μA, Referenced to 25 °C		2.2		mV/°C
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$		-1	-1.4	-2	V
			T _J = 125°C	-0.8	-1.08	-1.6	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_{D} = -15 \text{ A}$			0.037	0.042	Ω
			T _J = 125°C		0.053	0.075	
		$V_{GS} = -10 \text{ V}, I_{D} = -19 \text{ A}$			0.021	0.025	
D(on)	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	= -4.5 V, V _{DS} = -5 V				Α
g _{FS}	Forward Transconductance	$V_{DS} = -4.5 \text{ V}, I_{D} = -19 \text{ A}$			20		S
DYNAMIC C	HARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$	$V_{DS} = -15 \text{ V}, \ V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		1570		pF
C _{oss}	Output Capacitance	t = 1.0 MHz			975		pF
C _{rss}	Reverse Transfer Capacitance				360		pF
SWITCHING	CHARACTERISTICS (Note)						
t _{D(on)}	Turn - On Delay Time	$V_{DD} = -15 \text{ V}, I_{D} = -5 \text{ A},$			12.5	25	nS
t,	Turn - On Rise Time	$V_{GS} = -5 \text{ V}, R_{GEN} = 6 \Omega$	V_{GS} = -5 V, R_{GEN} = 6 Ω		60	120	nS
t _{D(off)}	Turn - Off Delay Time				50	100	nS
t _f	Turn - Off Fall Time				52	100	nS
Q _a	Total Gate Charge	$V_{DS} = -12 \text{ V}$ $I_D = -30 \text{ A}, V_{GS} = -5 \text{ V}$			26	36	nC
Q_{gs}	Gate-Source Charge				6.5		nC
$\overline{Q_{gd}}$	Gate-Drain Charge				11.5		nC
_	RCE DIODE CHARACTERISTICS			<u>I</u>	l	<u>I</u>	
I _s	Maximum Continuos Drain-Source Diode Forward Current					-30	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				-100	А	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -15 A (No	$V_{GS} = 0 \text{ V}, I_{S} = -15 \text{ A} \text{ (Note)}$		-0.92	-1.3	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{F} = -30 \text{ A}$			58		ns
Irr	Reverse Recovery Current	dl _ε /dt = 100 A/μs			-1.5		Α

Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2.0%.

Typical Electrical Characteristics

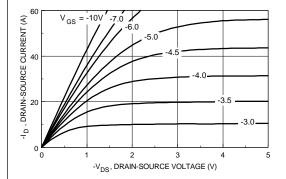


Figure 1. On-Region Characteristics.

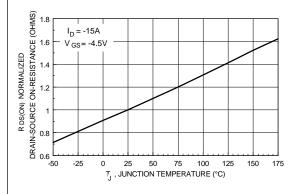


Figure 3. On-Resistance Variation with Temperature.

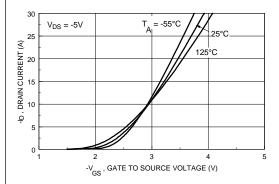


Figure 5. Transfer Characteristics.

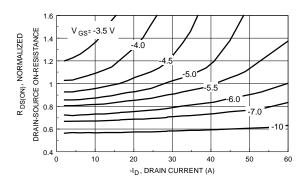


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

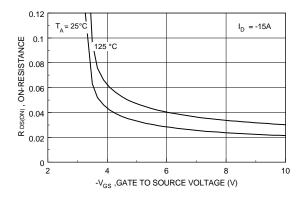


Figure 4. On Resistance Variation with Gate-To- Source Voltage.

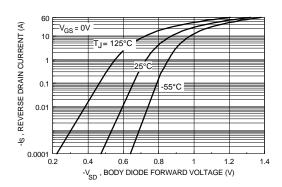


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics (continued)

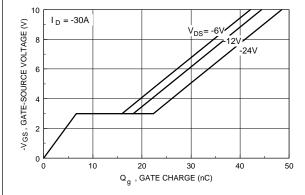


Figure 7. Gate Charge Characteristics.

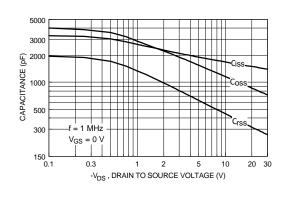


Figure 8. Capacitance Characteristics.

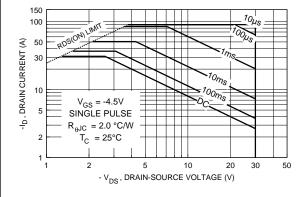


Figure 9. Maximum Safe Operating Area.

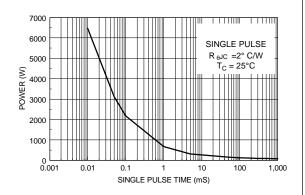


Figure 10. Single Pulse Maximum Power Dissipation.

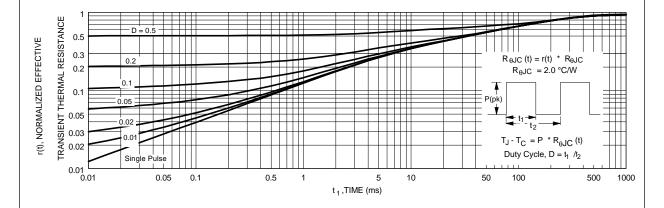


Figure 11. Transient Thermal Response Curve.

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